

Structural length-scale sensitivities of reflectance measurements in continuous random media under the Born approximation

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Which range of structures contributes to light scattering in a continuous random media, such as biological tissue? In this Letter, we present a model to study the structural length-scale sensitivity of scattering in continuous random media under the Born approximation. The scattering coefficient μ_s , backscattering coefficient μ_b , anisotropy factor g , and reduced scattering coefficient μ_s^* as well as the shape of the spatial reflectance profile are calculated under this model. For media with a biologically relevant Henyey–Greenstein phase function with $g \sim 0.93$ at wavelength $\lambda = 633$ nm, we report that μ_s^* is sensitive to structural length-scales from 46.9 nm to 2.07 μm (i.e., $\lambda/13$ to 3λ), μ_b is sensitive from 26.7 to 320 nm (i.e., $\lambda/24$ to $\lambda/2$), and the spatial reflectance profile is sensitive from 30.8 nm to 2.71 μm (i.e., $\lambda/21$ to 4λ). © 2012 Optical Society of America

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Elastic light scattering provides a valuable tool to *detect* and *quantify* subdiffractional structures even if they cannot be *resolved* by a conventional imaging system. However, the limits of the sensitivity of light scattering to different structural length-scales in a continuous random media (e.g., biological tissue) have not yet been fully studied. In this Letter, we present the methodologies used to study the length-scale sensitivities of the scattering parameters μ_s , μ_b , g , and μ_s^* as well as the diffuse reflectance profile in continuous random media.

Consider a statistically homogeneous random medium composed of a continuous distribution of fluctuating refractive index, $n(\vec{r})$. We define the excess refractive index which contributes to scattering as $n_\Delta(\vec{r}) = n(\vec{r})/n_o - 1$, where n_o is the mean refractive index. Since $n_\Delta(\vec{r})$ is a random process, it is mathematically useful to describe the distribution of refractive index through its statistical autocorrelation function $B_n(r_d) = \int n_\Delta(\vec{r})n_\Delta(\vec{r} - r_d)d\vec{r}$.

One versatile model for $B_n(r_d)$ employs the Whittle–Matérn family of correlation functions [1,2]:

$$B_n(r_d) = A_n \cdot \left(\frac{r_d}{l_c}\right)^{\frac{D-3}{2}} \cdot K_{\frac{D-3}{2}}\left(\frac{r_d}{l_c}\right), \quad (1)$$

where $K_\nu(\cdot)$ is the modified Bessel function of the second kind with order ν , l_c is the characteristic length of heterogeneity, A_n is the fluctuation strength, and D determines the shape of the distribution (e.g., Gaussian as $D \rightarrow \infty$, decaying exponential for $D = 4$, and power law for $D < 3$). Importantly, when $D = 3$ this model predicts a scattering phase function that is identical to the commonly used Henyey–Greenstein model.

All light scattering characteristics can be expressed through the power spectral density Φ_s . Under the Born approximation, Φ_s is the Fourier transform of B_n [2,3]:

$$\Phi_s(k_s) = \frac{A_n l_c^3 \Gamma\left(\frac{D}{2}\right)}{\pi^{3/2} 2^{(5-D)/2}} \cdot (1 + k_s^2 l_c^2)^{-D/2}, \quad (2)$$

where $k_s = 2k \sin(\theta/2)$ and k is the wavenumber.

In order to study the sensitivity of scattering to *short* length-scales (lower length-scale analysis), we perturb $n_\Delta(\vec{r})$ by convolving with a three-dimensional Gaussian:

$$G(\vec{r}) = \left(\frac{16\pi l_n(2)}{W^2}\right)^{3/2} \cdot \exp\left(\frac{-4l_n(2)}{W^2} r^2\right), \quad (3)$$

where W is the FWHM. Conceptually, $G(\vec{r})$ represents a process that modifies the original medium by removing “particles” smaller than W . Using the convolution theorem, this modified medium can be expressed as $n_\Delta^l(\vec{r}) = \mathcal{F}^{-1}[\mathcal{F}[n_\Delta(\vec{r})] \cdot \mathcal{F}[G(\vec{r})]]$, where \mathcal{F} indicates the Fourier transform operation and the superscript l indicates that lower frequencies are retained.

The autocorrelation of $n_\Delta^l(\vec{r})$ can then be found as

$$\begin{aligned} B_n^l(r_d) &= \mathcal{F}^{-1}[|\mathcal{F}[n_\Delta(\vec{r})]|^2 \cdot |\mathcal{F}[G(\vec{r})]|^2] \\ &= 4\pi \int_0^\infty \Phi_s^l(k_s) \frac{k_s \sin(k_s r)}{r} dk_s, \end{aligned} \quad (4)$$

where $\Phi_s^l(k_s)$ is the power spectral density for $n_\Delta^l(\vec{r})$ and can be computed as

$$\Phi_s^l(k_s) = \frac{A_n l_c^3 \Gamma\left(\frac{D}{2}\right)}{\pi^{3/2} 2^{(5-D)/2}} \cdot \frac{\exp\left(\frac{-k_s^2 W_l^2}{8l_n(2)}\right)}{(1 + k_s^2 l_c^2)^{D/2}}. \quad (5)$$

We note that Eq. (4) has no closed form solution, but can be evaluated numerically.

Figure 1 demonstrates the functions described by Eqs. (4) and (5) for varying values of W_l using a $B_n^l(r_d)$ with $D = 3$, $l_c = 1 \mu\text{m}$, and wavelength $\lambda = 633$ nm. This corresponds to a biologically relevant Henyey–Greenstein function with anisotropy factor $g \sim 0.93$. For increasing W_l , $B_n^l(r_d)$ shows a decreasing value at short length-scales [Fig. 1(a)]. The point at which $B_n^l(r_d)$ deviates from the original $B_n(r_d)$ corresponds roughly to the value of W_l . The lower value of $B_n^l(r_d)$ at short length-scales corresponds to decreased intensity

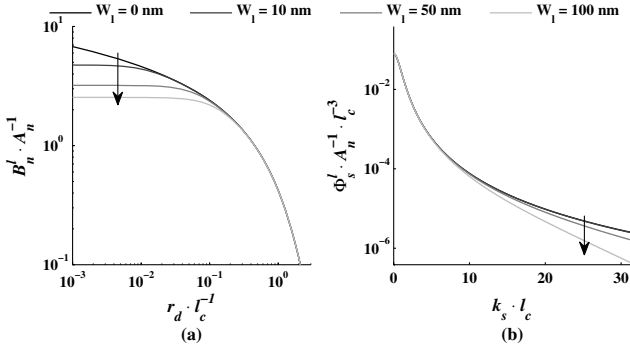


Fig. 1. Lower length-scale analysis for $W_l = 0, 10, 50,$ and 100 nm with $D = 3, l_c = 1$ μm , and $\lambda = 633$ nm. The normalized (a) $B_n^l(r_d)$ and (b) $\Phi_s^l(k_s)$. In each panel the arrow indicates increasing W_l .

of $\Phi_s^l(k_s)$ at higher spatial frequencies after Fourier transformation [Fig. 1(b)]. To study the sensitivity of scattering to *large* length-scales (upper length-scale analysis), we employ the same model as above but filter larger particles by evaluating $n_\Delta^h(\vec{r}) = \mathcal{F}^{-1}[\mathcal{F}[n_\Delta(\vec{r})] \cdot (1 - \mathcal{F}[G(\vec{r})])]$, where the superscript h indicates that higher frequencies are retained. The autocorrelation of $n_\Delta^h(\vec{r})$ can then be found as

$$\begin{aligned} B_n^h(r_d) &= \mathcal{F}^{-1}[|\mathcal{F}[n_\Delta(\vec{r})]|^2 \cdot |1 - \mathcal{F}[G(\vec{r})]|^2] \\ &= 4\pi \int_0^\infty \Phi_s^h(k_s) \frac{k_s \sin(k_s r)}{r} dk_s, \end{aligned} \quad (6)$$

where

$$\Phi_s^h(k_s) = \frac{A_n l_c^2 \Gamma\left(\frac{D}{2}\right)}{\pi^{3/2} 2^{(5-D)/2}} \cdot \frac{\left(1 - \exp\left(\frac{-k_s^2 W_h^2}{16m(2)}\right)\right)^2}{(1 + k_s^2 l_c^2)^{D/2}}. \quad (7)$$

Figure 2 shows the functions described by Eqs. (6) and (7). For decreasing W_h , $B_n^h(r_d)$ exhibits a decrease at larger length-scales [Fig. 2(a)]. These alterations lead to a decreased intensity of $\Phi_s^h(k_s)$ at lower spatial frequencies [Fig. 2(b)].

As a way to visualize the continuous media represented by the above equations, Fig. 3 provides example

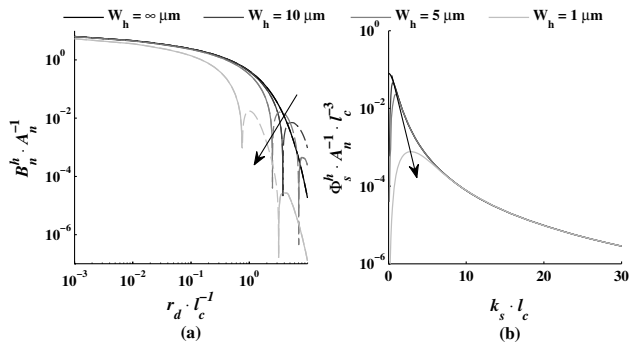


Fig. 2. Upper length-scale analysis for $W_h = \infty, 10, 5,$ and 1 μm with $D = 3, l_c = 1$ μm , and $\lambda = 633$ nm. (a) $B_n^h(r_d)$ where the dashed curves indicate locations in which the curve is negative. (b) $\Phi_s^h(k_s)$. In each panel the arrow indicates decreasing W_h .

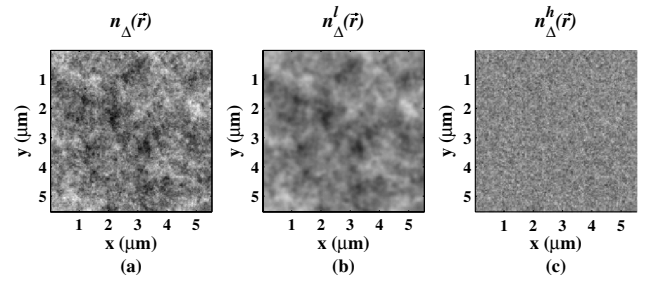


Fig. 3. Example media with $D = 3$ and $l_c = 1$ μm . (a) $n_\Delta(\vec{r})$, (b) $n_\Delta^l(\vec{r})$, and (c) $n_\Delta^h(\vec{r})$ for $W_l = W_h = 100$ nm.

cross-sectional slices through $n_\Delta(\vec{r})$, $n_\Delta^l(\vec{r})$, and $n_\Delta^h(\vec{r})$ for $D = 3, l_c = 1$ μm , and $W_l = W_h = 100$ nm.

Implementing the above methods, we now define a number of measurable scattering quantities. First, the differential scattering cross section per unit volume for unpolarized light $\sigma(\theta)$, can be found by incorporating the dipole scattering pattern into $\Phi_s(k_s)$:

$$\sigma(\theta) = 2\pi k^4 (1 + \cos^2 \theta) \Phi_s(k_s). \quad (8)$$

The shape of $\sigma(\theta)$ can be parameterized by the scattering coefficient μ_s , the backscattering coefficient μ_b , and g [4]:

$$\mu_s = 2\pi \int_{-1}^1 \sigma(\cos \theta) d \cos \theta, \quad (9)$$

$$\mu_b = 4\pi \cdot \sigma(\theta = \pi), \quad (10)$$

$$g = \frac{2\pi}{\mu_s} \int_{-1}^1 \cos \theta \cdot \sigma(\cos \theta) d \cos \theta. \quad (11)$$

Conceptually, μ_s is the total scattered power per unit volume, μ_b represents the power scattered in the *backward* direction per unit volume, and g describes how *forward* directed the scattering is. Finally, the effective transport in a multiple scattering medium is expressed by the reduced scattering coefficient $\mu_s^* = \mu_s \cdot (1 - g)$.

Figure 4(a) shows percent changes in the above scattering parameters under the lower length-scale analysis for a $B_n^l(r_d)$ with $D = 3, l_c = 1$ μm , and $\lambda = 633$ nm. With

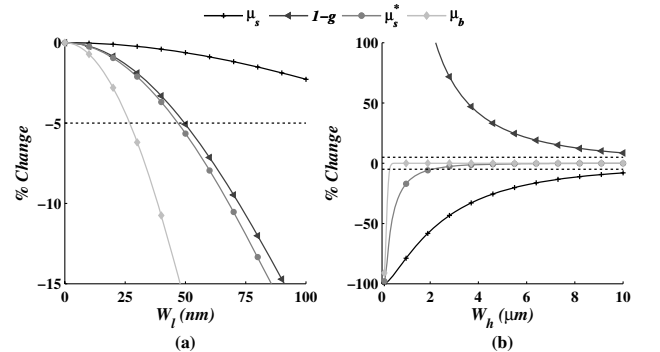


Fig. 4. Percent change in scattering parameters with varying values of W_l and W_h for $D = 3, l_c = 1$ μm , and $\lambda = 633$ nm. (a) Lower and (b) upper length-scale percent changes. The dotted line indicates the $\pm 5\%$ threshold.

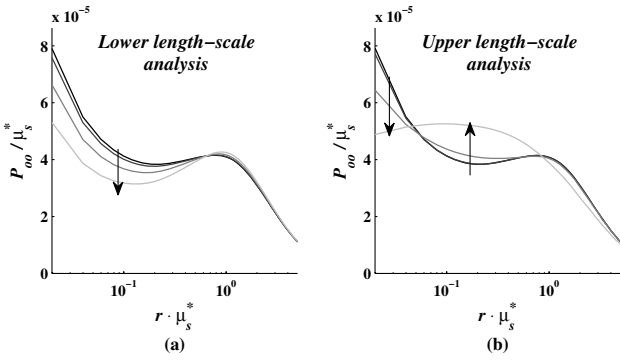


Fig. 5. Monte Carlo simulations of P_{oo} with $D = 3$, $l_c = 1 \mu\text{m}$, and $\lambda = 633 \text{ nm}$. (a) Lower length-scale analysis for $W_l = 0, 30, 60,$ and 90 nm . Arrow indicates increasing W_l . (b) Upper length-scale analysis for $W_h = \infty, 10, 2, 0.5 \mu\text{m}$. Arrows indicate decreasing W_h .

increasing W_l , each parameter decreases from its original value. For μ_s , the decrease occurs because scattering material is removed from the medium. For $1 - g$ and μ_b , the decrease occurs as a result of reduced backscattering [see Fig. 1(b)]. For μ_s^* , the decrease is a combination of the previous two effects.

To provide specific length-scale sensitivity quantification, we focus on the parameters most relevant to reflectance measurements: μ_s^* for samples within the multiple scattering regime and μ_b for samples within the single scattering regime. Defining a 5% threshold (a common significance level in statistics) the minimum length-scale sensitivity (r_{\min}) of μ_s^* and μ_b equals 46.9 nm ($\sim\lambda/13$) and 26.7 nm ($\sim\lambda/24$), respectively. Thus, measurements of μ_s^* and μ_b provide sensitivity to structures much smaller than the diffraction limit. Interestingly, r_{\min} is smaller for μ_b than μ_s^* . This can be understood by noting that k_s is maximized in the backscattering direction (i.e., $\theta = \pi$) and so provides the most sensitivity to alterations of $B_n(r_d)$ at small length-scales (see Fig. 1).

Figure 4(b) shows percent changes in the scattering parameters under the upper length-scale analysis. With decreasing W_h , μ_s decreases because scattering material is removed from the medium. For $1 - g$, an increase occurs due to a reduction in the forward scattering component. Combining these two opposing effects, the maximum length-scale sensitivity (r_{\max}) for μ_s^* equals $2.07 \mu\text{m}$ ($\sim 3\lambda$). For μ_b , a very small value of W_h is needed in order to alter backscattering. As a result, r_{\max} for μ_b is only 320 nm ($\sim\lambda/2$).

In order to study the length-scale sensitivity of the spatial reflectance profile we performed electric field Monte Carlo simulations of continuous random medium as described in [5]. Here, we display the distribution measured with unpolarized illumination and collection, $P_{oo}(r)$. $P_{oo}(r)$ is the distribution of light that exits a semi-infinite medium antiparallel to the incident beam and within an annulus of radius r from the entrance point. It is normalized such that $\int_0^\infty P_{oo}(r) dr = 1$.

Figure 5(a) shows P_{oo} under the lower length-scale analysis for a $B_n(r_d)$ with $D = 3$, $l_c = 1 \mu\text{m}$, and

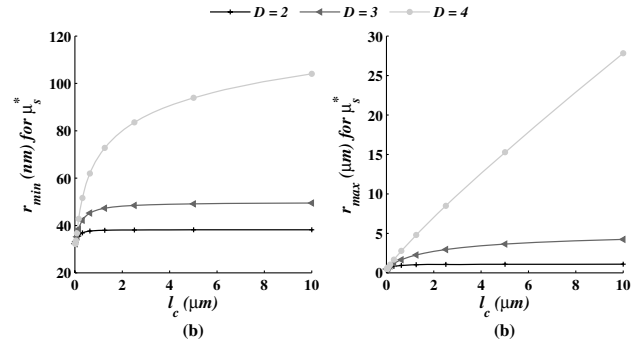


Fig. 6. (a) r_{\min} and (b) r_{\max} for μ_s^* with different shapes of $B_n(r_d)$ and $\lambda = 633 \text{ nm}$.

$\lambda = 633 \text{ nm}$. With increasing W_l , the value of P_{oo} is decreased within the subdiffusion regime (i.e., $r \cdot \mu_s^* < 1$). This decrease can be attributed in part to the decreased intensity of the phase function in the backscattering direction [see Fig. 1(b)]. For $r \cdot \mu_s^* > 1$, a range that is essentially insensitive to the shape of the phase function, P_{oo} remains largely unchanged. Figure 5(b) shows similar results for the upper length-scale analysis. In order to perform a sensitivity analysis, we calculate the maximum percent error at any position on P_{oo} relative to the original case. Applying a 5% threshold once again, we find that $r_{\min} = 30.8 \text{ nm}$ ($\sim\lambda/21$) and $r_{\max} = 2.71 \mu\text{m}$ ($\sim 4\lambda$).

Finally, we note that the exact values of r_{\min} and r_{\max} depend on the shape of $B_n(r_d)$. The values given above provide an estimate assuming a correlation function shape that is widely used and accepted for modeling of biological tissue (Heney-Greenstein). Figure 6 illustrates the dependence of r_{\min} and r_{\max} on the shape of $B_n(r_d)$, assuming the Whittle-Matérn model and using μ_s^* as an example. As either D or l_c increases, $B_n(r_d)$ shifts relatively more weight to larger length-scales and away from smaller length-scales. As a result, both r_{\min} and r_{\max} increase monotonically with D and l_c .

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